

Deuterium retention in MeV self-implanted tungsten: influence of damaging dose rate

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Abstract.

Recrystallized, polycrystalline tungsten was self-damaged by 20 MeV tungsten ions up to a calculated damage dose in the damage peak of 0.23 dpa. The time to acquire this dose and hence the average damaging dose rate was varied from 6×10^{-3} to 4×10^{-6} dpa/s, the latter coming close to the damage dose rate expected from fusion neutrons in future devices such as ITER and DEMO. One series was conducted at 295 K and one at 800 K to check for possible effects of defect evolution at elevated temperature. The created damage was decorated afterwards with a deuterium plasma at low ion energy of < 15 eV and low flux of 5.6×10^{19} D/m² until saturation to derive a measure for the defect density that can retain hydrogen isotopes. ³He nuclear reaction analysis (NRA) was applied to derive the deuterium depth profile and the maximum concentration in the damage peak. Neither for the 295 K nor for the 800 K series a variation in deuterium retention with damage dose rate was found.

Keywords: tungsten, deuterium retention, displacement damage, plasma, NRA, Plasma-material interactions, ion radiation effects

26 **1. Introduction**

27

28 Taking co-deposition with low-Z elements aside hydrogen isotopes retention in present-
29 day fusion devices with tungsten walls is limited by intrinsic and near-surface, plasma-
30 induced defects. In contrast, in a future thermonuclear fusion device additional trapping
31 sites will be created throughout the tungsten bulk by fast fusion neutrons which will
32 potentially increase retention by orders of magnitude. Recent experiments with fission-
33 neutron-irradiated tungsten show after deuterium plasma exposure deuterium
34 concentrations of up to 0.8 at.% at 200°C [1]. However, these studies are hampered by
35 the fact that neutron exposure conditions are not well defined in terms of temperature and
36 dose rate. In addition handling and analysis of these activated samples are typically very
37 limited, turn-around times are long, experiments are expensive, and because of that
38 samples are typically few. Systematic parameter studies are therefore not available. To
39 overcome these limitations, ions with energies of tens of keV to MeV are often used as
40 surrogates to create displacement damage. They are successfully applied since decades in
41 fission material development for lifetime tests such as swelling [2]. For fuel retention
42 studies in tungsten, high energy ion implantation is used since many years and it is still a
43 field of active research [3, 4, 5, 6, 7]. Contrary to neutron irradiation, ion-beam
44 irradiation is fast and does not activate the samples. However, it is still unclear in how far
45 the observations gained with this ion-beam-damaged surrogate material can be
46 transferred to material damaged with fusion neutrons. Different ions and different
47 energies are used and it is not clear in which case the displacement damage resembles
48 best the defect structure created by the collision cascades with fast fusion neutrons. One

49 parameter that was not addressed yet is the vast difference in the damage creation rate
50 between ion-beam damaging and damage created by fusion neutrons. There is some
51 doubt that the biggest advantage of high energy ion implantation, namely its accelerated
52 speed, might create artefacts that would not be present if damage creation would be
53 conducted at the rate expected in the future fusion application. While for the latter
54 damage doses in the dpa range are acquired over a year they can be collected within
55 hours with an ion beam or even faster and hence damaging dose rates for ion-beam
56 damaging are typically at least two to three orders of magnitude larger than expected for
57 future fusion devices. A prominent example for a rate-dependent effect in ion-beam
58 irradiation of materials is the peak swelling temperature in steels that was found to be
59 higher for higher dose rates in simple metals such as copper, nickel or stainless steel [2].
60 Because of this rate dependence of such swelling experiments it was also concluded that
61 it is not advisable to scan the ion beam with high frequency over the sample when trying
62 to simulate neutron damage [2]. Nevertheless it is applied in most studies on D retention
63 in order to achieve a homogenous implantation profile as it facilitates later analysis.
64 Unfortunately such essential experimental details are very often not even mentioned
65 explicitly in the literature which hampers the comparability of results even between these
66 surrogate studies. In this contribution the experimental setup for MeV ion implantation
67 used over the last years at IPP Garching is first explained in detail. Second, results on
68 deuterium retention for tungsten implantation into tungsten – so-called self damaging –
69 will be presented. Special emphasis is placed on the influence of the damaging dose rate
70 on retention. Damaging with continuous and scanned ion beam will be compared.
71

72 **2. . Experiment**

73 Hot-rolled tungsten with a purity of 99.97 wt.%. manufactured by Plansee AG
74 (Austria) [8] was used in this study. In order to assure comparability and to minimize the
75 influence of micro-structural effects all W samples were from the same manufacturing
76 batch as in preceding studies [6, 7, 9, 10, 11, 12] 13, 14, 15]. For this study the sample
77 size was $10\times 10\times 0.8\text{ mm}^3$. The main impurity, excluding Mo, in this W grade is carbon
78 and iron with less than $30\text{ }\mu\text{g/g}$ each. To allow for reliable determination of depth profiles
79 with ion-beam methods the surfaces were chemo-mechanically polished to a mirror-like
80 finish following the procedure outlined in reference [10].

81 The aim of this study was to focus on the defects created by the self-damaging.
82 Therefore, intrinsic defects as well as possible gaseous inclusions were minimized by re-
83 crystallizing the specimen in vacuum. First, samples were carefully outgassed and finally
84 heated to 2000 K for 2 min by electron bombardment while maintaining the pressure in
85 the low 10^{-6} Pa range. The temperature was measured with a disappearing filament
86 pyrometer during this procedure. As a consequence of this re-crystallization, the initial
87 dislocation density of $2\times 10^{12}\text{ m/m}^3$ is reduced by two orders of magnitude compared to
88 the as-delivered state [11]. The material exhibits grains with a size distribution ranging
89 from $10\text{ }\mu\text{m}$ to $50\text{ }\mu\text{m}$ as observed by scanning electron microscopy and by confocal
90 scanning laser microscopy. An image of a representative surface area of $100\text{ }\mu\text{m}$ by
91 $133\text{ }\mu\text{m}$ is shown in figure 1. Because recrystallization is performed after polishing,
92 distortions introduced by the polishing procedure are annealed out, too.

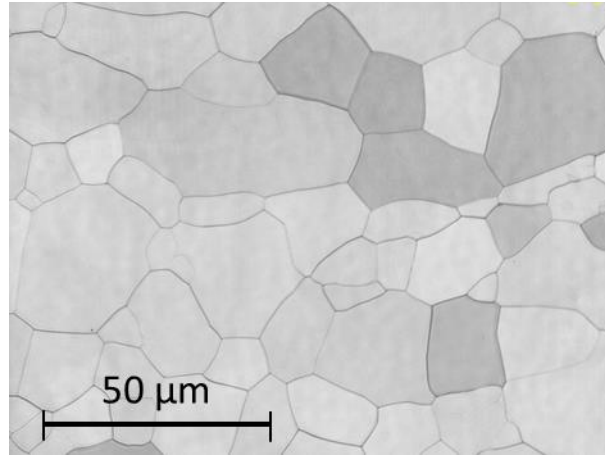


Figure 1: Confocal laser scanning microscopy image of a sample surface after polishing and annealing at 2000 K for 2 min in UHV.

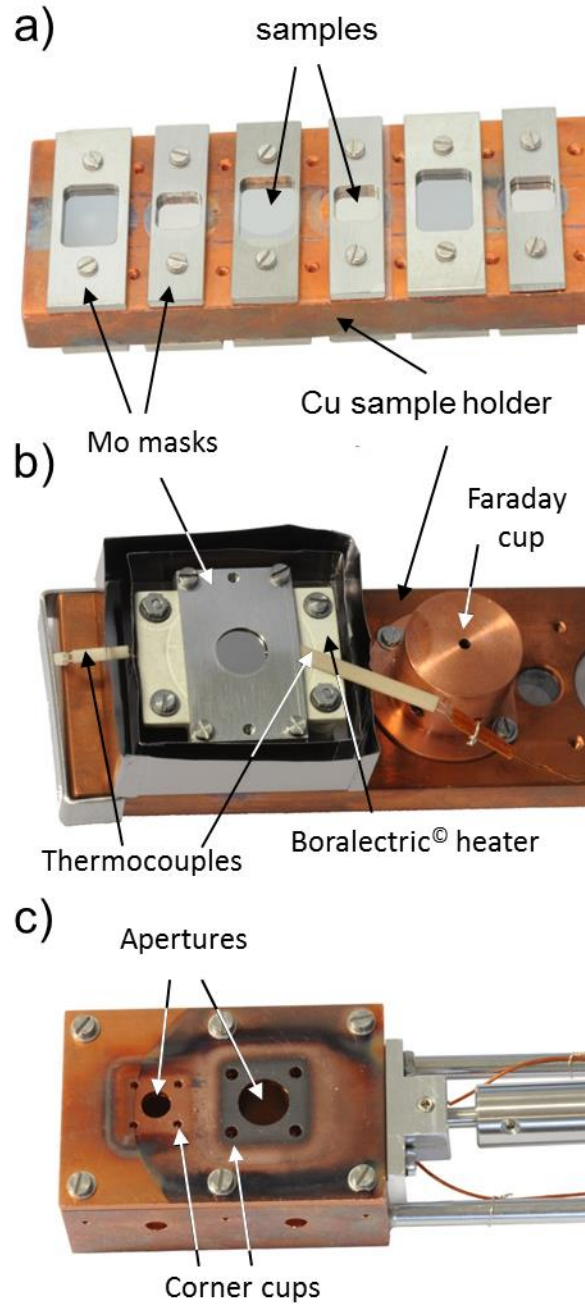


Figure 2: Sample holders for MeV tungsten implantation used in this study. a) water-cooled holder with $10 \times 10 \text{ mm}^2$ samples and $12 \times 15 \text{ mm}^2$ reference samples clamped down with molybdenum masks. b) holder for implantation at elevated temperature showing the Boralectric® heating element, the two thermocouples, the Mo radiation shields, a sample installed with the molybdenum mask and the faraday cup for beam characterization. c) beam-defining, water-cooled apertures 7 mm and 12 mm in diameter together with the four corner cups for in situ current measurement.

94 Damaging was done by tungsten self-implantation with 20 MeV W^{6+} ions in the
95 TOF beamline of the 3 MV tandemron accelerator. Tungsten ions were created with a
96 cesium sputter source from a tungsten carbide target. For the first experimental series
97 samples were directly clamped down with a molybdenum mask on a water-cooled copper
98 substrate holder as shown in figure 2a. The mask opening area was $9 \times 9 \text{ mm}^2$ in this
99 case. For the second series at elevated temperature, samples were mounted directly on a
100 resistive heater (Boralectric[®] HTR1001) and also clamped down with a molybdenum
101 mask as shown in figure 2b. A rectangular mask with a circular opening of 9 mm in
102 diameter was used in this case. In the present high-temperature design two thermocouples
103 are used to allow for reliable temperature control of the sample. One type K
104 thermocouple was inserted into a small hole at the side of the heater itself, a second type
105 K thermocouple was clamped between the sample and the mask as shown in figure 2b.
106 To minimize outgassing and to achieve a quick response time to temperature changes the
107 heater is mounted on a water-cooled support structure and surrounded by molybdenum
108 shields as can be seen in figure 2b, too. Typically the W beam is focused onto the target
109 position with an electrostatic quadrupole triplet lens and scanned over an area of up to
110 25 mm by 25 mm to achieve a homogenous flux throughout the implantation area. For
111 the latter x- and y-deflection plates are used whose voltage supply is ramped with two
112 triangle wave-shaped crystal-locked scan frequencies of close to 1 kHz. Water-cooled
113 copper apertures with different size are placed in front of the sample holder arrangement
114 that have four faraday cups in the corners and a central hole as shown in figure 2c. When
115 the beam is spread out to cross the four corner cups, the absolute tungsten flux can be
116 calculated from the measured current and the cup surface areas. A central hole in the

117 copper aperture defines the beam that finally hits the sample. This aperture is aligned
118 with the sample mask using an optical telescope on axis. For this study, arrangements
119 with a central hole of 12 mm and 7 mm in diameter were used. Figure 3 shows
120 experimental results to characterize the beam. To measure its width the beam was
121 focused and steered into one of the four corner cups with a diameter of 2 mm while
122 manually moving the cup (red circles and left scale). In addition, deuterium retention
123 measured with NRA of a sample implanted with 20 MeV W^{6+} with the focused beam to a
124 fluence of 7.87×10^{17} W/m^2 and subsequently exposed to D plasma at 295 K till saturation
125 is reached. Figure 3 shows integrated proton counts from the $D(^3He,p)\alpha$ nuclear reaction
126 measured with a 3He energy of 2.4 MeV while scanning laterally over the sample (blue
127 stars and the right scale). The analyzing spot width was 1 mm in that case. Both
128 experiments show the same beam width at half maximum of 2 mm.

129 Also shown in Figure 3 are the integrated proton counts of a sample implanted
130 with the beam spread out to homogenize the implantation (open blue squares). The
131 sample was also exposed to D plasma to decorate the defects until saturation at 295 K and
132 measured with a 3He energy of 2.4 MeV while scanning laterally over the sample. The
133 observed variation in D retention of 2 % is within the accuracy of the NRA analysis. We
134 hence conclude a homogeneity of the W implantation of better than 2 %.

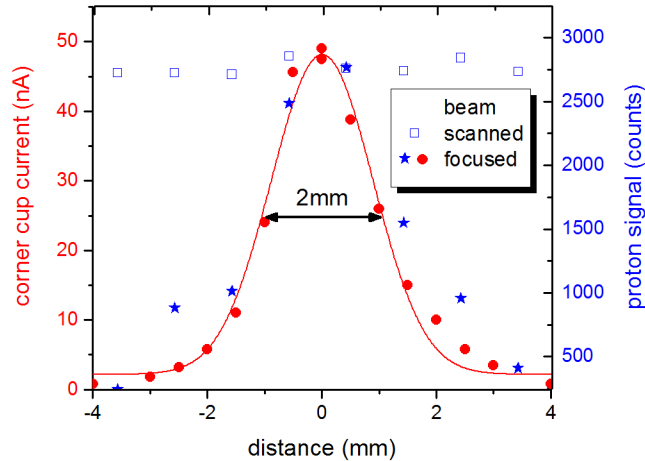


Figure 3: Beam-profile measurement of the focused W beam. Red circles and left scale show the current measured in one of the four corner cups while manually moving the cup. In blue and the right scale integrated proton counts from the $D(^3\text{He},p)\alpha$ reaction are shown from a scan laterally over the sample implanted with the focused beam (blue stars) and the scanned W beam (open squares). ^3He energy 2.4 MeV. In addition a Gaussian curve is plotted to guide the eye.

135 The current measurement from which the average W flux and hence the total
 136 fluence is deduced was cross checked with implanting W^{2+} with an energy of 1 MeV and
 137 a fluence of $1.6 \times 10^{20} \text{ W/cm}^2$ into mirror-polished pyrolytic graphite and subsequent
 138 Rutherford Backscattering Spectrometry of the implanted tungsten amount with 1 MeV
 139 protons. Comparison of the measured spectra with SIMNRA 6.06 [16] simulation yields
 140 an accuracy better than 10% for the absolute amount of tungsten and hence for the W ion
 141 current measurement.

142 The measure for the damage dose is derived in this work by evaluating the
 143 computed displacements from SRIM-2008.04 calculations [17]. Care must be taken when
 144 comparing this quantitatively to values stated in the literature. Besides obvious
 145 differences when using different displacement energies (e.g. 68 eV in [5], or 90 eV in
 146 [18] subtle changes can exist using different releases of the code as well as different
 147 calculation volume or number of ions. Much more seriously, with the very same

148 parameters but different calculation options (“Quick Kinchin Pease” or “Full Cascade”)
149 or evaluating different output files (vacancy.txt or e2recoils.txt) there might be a
150 difference up to a factor of two depending on the procedure applied as stressed by Stoller
151 et al. and Nordlund et al. [19, 20]. These two studies recommend using the “Quick
152 Kinchin Pease” option and it is hence used in this study. Unfortunately, most of the work
153 to be found for self-damage tungsten in literature till now applied the “Full cascade”
154 option, but in none of them the necessary input parameters and procedures applied are
155 given. In this study “dpa” values are calculated using SRIM-2008.04 adding the “recoil”
156 and “ion” displacements from the “vacancy.txt” output file and converting the sum with
157 the ion fluence and the tungsten density to get a depth profile of the number of displaced
158 target atoms and the damage dose in “displacements per atom”, in short “dpa”.
159 Replacement collisions are neglected. A displacement energy of 90 eV as recommended
160 by the American Society for Testing and Materials [21] is used and a lattice binding
161 energy of 0 eV. The results of the here applied “Quick Kinchin Pease” calculation option
162 are compared with those of the “Full Cascade” calculation option to allow easy
163 comparison with existing values in literature. For the here investigated case of 20 MeV
164 tungsten self-implantation the “vacancy.txt” output yields for the “Quick Kinchin Pease”
165 calculation 1.86 displacements per ion and Ångström in the peak maximum while it is
166 4.05 displacements per ion and Ångström for the “Full cascade” option and hence a factor
167 of 2.2 less. It is important to note here that this factor is not unique, but varies with
168 energy.

169 Loading of the samples with deuterium was performed in the well-characterized
170 low-temperature plasma experiment PlaQ [22]. To decorate only the existing defects with

171 deuterium without creating additional trapping sites, deuterium exposure was performed
172 with floating target holder. At a D₂ background pressure of 1.0 Pa this results in an ion
173 energy below 15 eV. Because the ion flux consists mainly of D₃⁺ ions (94 %) with minor
174 contributions of D₂⁺ (3 %) and D⁺ (3 %) [22] I refer to this setting as <5 eV/D. For this
175 condition the resulting deuterium flux in the form of ions is 6×10¹⁹ D/m²s. The flux of
176 neutral atomic deuterium of low energy (< eV) exceeds the flux of ions by at least one
177 order of magnitude [22]. However, contributions of neutral atomic deuterium are
178 neglected here and flux refers here to the ion flux only. All samples of one damage-rate
179 series were always D loaded at the same time. Each sample was tightly screwed at the
180 four corners with molybdenum screws to a tungsten-coated copper target holder. To
181 avoid any defect annealing or defect evolution a sample temperature of 295 K was set
182 during D loading. The time was chosen large enough to allow for D diffusion into the
183 depth which is for the given defect density and depth distribution achieved after 72 hours
184 of exposure or a D fluence of 1.5×10²⁵ D/m². The temperature of the target holder was
185 maintained by a liquid cooling circuit connected to a thermostat operated with ethanol at
186 293 K. Sample temperature was measured with a type K thermocouple spring loaded
187 through a hole in the sample holder touching the back side of one sample. In addition, an
188 IR camera was used to monitor the temperature evolution as well as the lateral
189 homogeneity of all samples during the experiments.

190 Deuterium depth profiles were analysed ex-situ with the D(³He,p)α nuclear
191 reaction with eight different ³He energies varying from 500 keV to 4.5 MeV to probe a
192 sample depth of up to 7.4 μm. The D concentration within the near-surface layer at
193 depths of up to about 0.3 μm was determined with ³He energies of 500 keV, 690 keV and

194 800 keV by analyzing the emitted α particles with a surface barrier detector at the
195 laboratory scattering angle of 102° . A rectangular slit in front of the detector reduces the
196 solid angle to 8 msr but increases resolution. For determining the D concentration at
197 larger depths, the high energy protons were analysed using a thick, large-angle solid state
198 detector at a scattering angle of 135° . A curved slit is installed in front of the detector to
199 increase resolution which reduces the solid angle to 75 msr. A nominal charge of $10 \mu\text{C}$
200 was usually accumulated for each energy. Under 165° backscattered ^3He was detected
201 with a small surface barrier detector to accurately determine the actually acquired total
202 charge collected for each energy by simulating the spectra with SIMNRA 6.06 [16].
203 NRADC [23] was used for the deconvolution of the spectra measured at different ^3He ion
204 energies. As input data for NRADC all α and proton spectra measured at the different
205 energies were analysed simultaneously. Details about the data evaluation using NRADC
206 can be found in Ref. [23]. The present version of NRADC allows to define a depth
207 resolution as a function of depth within the Markov chain sampling. If a layer thickness
208 below that physical limit is proposed this solution is rejected. ResolNRA [24] was
209 applied to define this physical limit. For the quantitative analysis we used the cross
210 section recently published by Wielunska et al. for the protons [25] and Möller and
211 Besenbacher for the α particles [26]. The total amount of D retention up to a depth of
212 $7.4 \mu\text{m}$ was finally determined by integrating the D profile over depth. For energy
213 calibration purposes, to check the performance of the detectors and to calibrate the solid
214 angles of all detectors in-situ amorphous, deuterated carbon thin film samples ($\alpha\text{-C:D}$)
215 were measured always together with the samples of interest for each energy. With these
216 precautions the accuracy of the measurement can be reduced to that of the beam-current

217 measurement which is 3 %. Given the counting statistics (counts depending on D content
218 and energy) the absolute accuracy of the measurements reduces to the absolute accuracy
219 of the cross section which is stated as 5 % [26].

220 **3. Results and discussion**

221

222 One possible way of changing the implantation flux and hence the damage dose
223 rate would be to use different charges states, because their abundance varies after
224 stripping the primary W⁻ beam at the terminal of the tandem accelerator. However, for a
225 fixed terminal voltage this leads to different energies of the particles and hence the
226 ambiguity introduced by the different SRIM outputs would make it complicated to
227 compare. Alternatively one could adjust the energy such that the product of charge state
228 and energy stays the same. However, one would reduce the implantation depth to well
229 below half a micron which is impractical as it is then below the depth resolution of the
230 NRA method. Because of the uncertainty in dpa calculations and the limited accessible
231 dynamic range the W implantation energy was kept fixed at 20 MeV in the experimental
232 series presented here, and the tungsten flux was varied instead. By doing this, one can
233 directly compare the experimental results as they are independent from the actual damage
234 profile or the absolute damage dose level.

235 A previous study for this material grade with 20 MeV self-implantation at room
236 temperature showed that below a damaging fluence of 1.6×10^{16} W/m² deuterium
237 retention increases linearly with damage dose, starts to deviate at higher fluences and
238 finally saturates [15]. Above 7.87×10^{17} W/m² no further increase in maximum deuterium
239 concentration and deuterium retention with damage dose was observed. This damage
240 saturation regime is selected for this study. Figure 4 shows the respective SRIM

241 calculation converted into damage dose. For the “Full cascade” option a peak damage
242 dose level of $0.5 \text{ dpa}_{\text{FC}}$ is obtained for this fluence, while it is $0.23 \text{ dpa}_{\text{KP}}$ for the “Quick
243 Kinchin Pease” option as depicted in figure 4. In addition to the SRIM profile the
244 deuterium depth profile is shown in figure 4. It was derived by deconvoluting the NRA
245 data for a sample self-damaged with the standard conditions comparable to those in
246 previous publications (see [7, 14, 15]) and decorated with D plasma at 295 K. Here, the
247 tungsten beam was spread out to reach the four corner cups to have real time control of
248 the implantation flux. Under these standard conditions one needs an implantation time of
249 43 minutes to reach the intended dose of $7.87 \times 10^{17} \text{ W/m}^2$ and hence the average damage
250 dose rate is $8.9 \times 10^{-5} \text{ dpa}_{\text{KP}}/\text{s}$. It is important to recall here that this value is an average
251 dose rate. The peak dose rate is larger due to the beam scanning with 1 kHz. From the
252 measured beam width shown in figure 2 and the actual scan width the peaking factor can
253 be derived which is in the present experiment a factor of 65 and hence the peak damage
254 dose rate is $5.8 \times 10^{-3} \text{ dpa}_{\text{KP}}/\text{s}$.

255 Because of the mentioned saturation with damage dose above $0.1 \text{ dpa}_{\text{KP}}$ the final
256 D depth profile at the here investigated $0.23 \text{ dpa}_{\text{KP}}$ is not expected to follow the SRIM
257 calculation, but should be rather flat in accordance to the experimental observation. As
258 can be also seen in figure 4 the maximum depth coincides well with the depth predicted
259 by SRIM. The error bars given in the depth profile reflect only the statistical uncertainties
260 determined by NRADC and, thus do not describe the total uncertainty of the
261 measurement mentioned in the previous section. The total amount of deuterium retained
262 in the self-damaged layer is $2.3 \times 10^{21} \text{ D/m}^2$. In the following the maximum deuterium
263 concentration (at the position of the damage peak, i.e. at about $1.3 \mu\text{m}$) will be used as it

264 is easier to compare to implantations at different ion energies, different ions or even to
265 neutron-irradiated material. The maximum deuterium concentration for this experiment is
266 1.9 at.%.

267 As stated in the previous section the average implantation flux can be reduced by
268 spreading the beam with the beam sweeping system even further - in the present case by
269 another factor of four compared to the standard condition outlined before. However, by
270 doing so the peaking factor is increased accordingly and hence the peak damage dose rate
271 is not reduced. However, the primary tungsten flux can be reduced by reducing the
272 temperature of the molybdenum thermal ionizer in the sputter source to reduce the
273 primary cesium ion flux. By doing so, the peak damage dose rate can be reduced by a
274 factor of five. By applying both, the time to reach $0.23 \text{ dpa}_{\text{KP}}$ was increased to 16.5 hours
275 in that way. This converts to an average damage dose rate of $3.9 \times 10^{-6} \text{ dpa}_{\text{KP}}/\text{s}$ or a peak
276 rate of $1.3 \times 10^{-3} \text{ dpa}_{\text{KP}}/\text{s}$. The obtained depth profile is within the accuracy of the method
277 identical to the one shown in figure 4 and the maximum deuterium concentration is
278 1.8 at.%.

279 To measure the peak damage dose rate for the standard conditions the beam scanning unit
280 was switched off and the W beam was focused into one of the Faraday cups to measure
281 the W flux. In addition, one target was implanted with this focused beam. By doing this
282 the intended W fluence can be acquired within 40 seconds which converts to a dose rate
283 of $5.8 \times 10^{-3} \text{ dpa}_{\text{KP}}/\text{s}$ in perfect accordance with the value derived from the peaking factor
284 above. Again, the obtained depth profile is within the accuracy of the method identical to
285 the one shown in figure 4. The maximum deuterium concentration in this case is again
286 1.8 at.%. The maximum concentrations of these three measurements are plotted as

287 function of average damage dose rate in figure 5a and as function of peak damage rate in
288 figure 5b. It is also worth mentioning that the sample prepared with the continuous beam
289 shows the identical D retention as a sample prepared with a different average damage rate
290 but the same peak damage rate. In summary, variation of the average damage dose rate by
291 three orders of magnitude between 5.8×10^{-3} to 3.9×10^{-6} dpa_{KP}/s or the peak damage rate
292 by a factor of five between 5.8×10^{-3} to 1.3×10^{-5} dpa_{KP}/s does not influence deuterium
293 retention when damaging is conducted at room temperature. Assuming a typical size of a
294 cascade of several tens of nanometer, the given damage creation rate and a typical life
295 time of the primary damage of a few tens of picoseconds [2] this result could have been
296 expected. However, it was not clear from the beginning if longer-time scale effects play a
297 role in damage evolution caused by thermally activated processes. While vacancies are
298 immobile at room temperature due to their large migration barrier of 1.6 eV, tungsten
299 interstitials can migrate (0.05 eV migration barrier) [27]. Although these two defect types
300 are only the easiest to consider and self-damaged tungsten contains many more defect
301 types such as vacancies clusters of different size and dislocations of different geometries
302 their energies are here only used for illustration. Obviously the timescales for defect
303 evolution are shorter as would be required to have any effect on deuterium retention.
304 Likewise defect evolution – such as clustering of vacancies - could take place without
305 influencing deuterium retention.

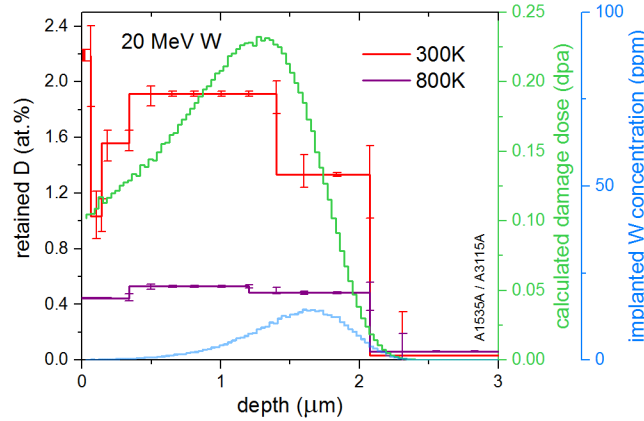


Figure 4: Deuterium depth profile for 20 MeV self-damaged tungsten samples implanted with W^{6+} at 295 K and 800 K with an implantation fluence of $7.87 \times 10^{17} \text{ W/m}^2$ and an average dose rate of $8.9 \times 10^{-5} \text{ dpa/s}$. D decoration was done for 72 h ($1.45 \times 10^{25} \text{ D/m}^2$) with $<5 \text{ eV/D}$ at 295 K. In addition the damage dose (green) and the implanted tungsten concentration (blue) calculated with SRIM 2008.04 as described in the text is shown on the right axis.

306 According to Keys and Moteff annealing of defects in tungsten sets in at 0.15
 307 times the melting temperature which corresponds to 550 K [28]. Therefore, the
 308 experimental sequence was repeated well above that temperature, namely at a damaging
 309 temperature of 800 K. Again the average and peak damage dose rate was varied in the
 310 same manner as before. Again the depth profile obtained for the sample prepared with
 311 “standard” conditions and decorated with D by a deuterium plasma at 295 K is show in
 312 figure 4. As expected the depth profile is again flat and reaches to the same depth as for
 313 the samples damaged at 295 K. Due to defect evolution at 800 K the number of traps is
 314 reduced and hence the deuterium concentration found in this sample is substantially
 315 lower. The maximum deuterium concentration is 0.55 at-% and hence a factor of 3.5
 316 smaller than for the samples damaged at 295K. The total amount of deuterium retained in
 317 the self-damaged layer is $5.4 \times 10^{20} \text{ D/m}^2$. It is worth mentioning that deuterium uptake for
 318 these samples damaged at 800 K is substantially larger than observed in an independent
 319 study of the same material conducted recently [29]. There the tungsten samples self-
 320 damaged at 800 K were loaded with a beam of atomic deuterium at 600 K and a
 321 maximum concentration of 0.14 at.% was observed. Hence thermal detrapping between D
 322 loading at 295 K and at 600 K reduces D retention by a factor of four for this type of self-
 323 damaged material.

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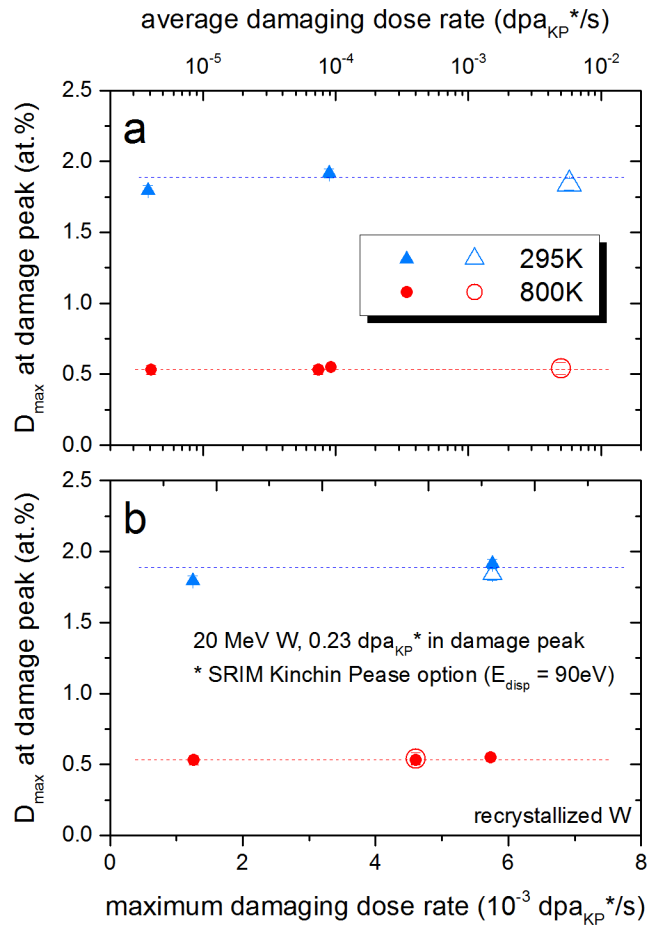


Figure 5: Maximum deuterium concentration in the self-damaged zone for recrystallized tungsten damaged with 20 MeV W^{6+} at 295 K and 800 K as function of a) average damaging dose rate and b) peak damage dose rate. D decoration was done for 72 h (1.45×10^{25} D/m²) with <5 eV/D at 295 K. Closed symbols: scanned beam, open symbols: continuous beam.

325

326 Figure 5 shows the maximum concentrations of this experimental series for all
 327 samples conducted in the same way as the first one except that damaging was conducted
 328 at 800 K. Also here, variation of the damage dose rate does not influence deuterium
 329 uptake. This is rather surprising. Reduction in D retention by a factor of 3.5 clearly points
 330 towards a reduced defect density and hence defect evolution taking place between 300 K
 331 and 800 K as shown also in [29]. One could therefore expect an influence of the damage
 332 rate. Obviously time scales in defect evolution are faster than defined by these damage
 333 rates.

334 In a recent study Gilbert et al. calculated the expected damage for DEMO to be
335 smaller than 14 dpa per full power year which converts to a damage rate of around
336 4×10^{-7} dpa/sec. [30]. In a recent work by You et al. even smaller values for damage
337 creation in DEMO are mentioned which convert to damage rates of 2×10^{-7} dpa/s [31].
338 Both values are at least one order of magnitude smaller than the average damage rates
339 and more than three orders of magnitude smaller than the peak damage rate accessible in
340 this experimental work. However, given the fact that no influence of deuterium retention
341 is observed for these high rates one can safely assume that for even smaller damage dose
342 rates no influence on D retention is present. Likewise one could conclude from these
343 experiments that the use of a scanned ion beam instead of a continuous beam has no
344 tremendous effect on deuterium retention studies as could have been anticipated from the
345 experience on swelling.

346

347 **4. Conclusions**

348

349 Deuterium retention was measured in recrystallized tungsten implanted with 20 MeV
350 tungsten ions at 295 K and 800 K for different damaging dose rates. Changing the
351 average damaging dose rate by three orders of magnitude between 6×10^{-3} to 4×10^{-6} dpa/s
352 or the peak damage dose rate by a factor of five does not influence D retention. Neither
353 for the room temperature series, nor for the 800 K series, where defect evolution clearly
354 takes place, as can be seen by the reduced deuterium uptake. Obviously, the time scales
355 for defect evolution are short enough to happen in between single cascade events in both
356 cases. As damaging rates by fusion neutrons in future fusion devices will be even smaller
357 and hence timescale between events larger no effect of the lower damage rates on D

358 retention in a future reactor is to be expected However, as neutrons will not only create
359 displacement damage but will also lead to transmutation and gas production care must be
360 taken when extrapolating results from ion-beam-damaged tungsten to fission or fusion
361 neutron damaged tungsten in general.

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376 **References**

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